



MODELING Cu MIGRATION IN CDTe SOLAR CELLS UNDER DEVICE-PROCESSING AND LONG-TERM STABILITY CONDITIONS

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Abstract

An impurity migration model for systems with material interfaces is applied to Cu migration in CdTe solar cells. In the model, diffusion fluxes are calculated from the Cu chemical potential gradient. Inputs to the model include Cu diffusivities, solubilities, and segregation enthalpies in CdTe, CdS and contact materials. The model yields transient and equilibrium Cu distributions in CdTe devices during device processing field-deployed conditions. under and Preliminary results for Cu migration in CdTe PV devices using available diffusivity and solubility data from the literature show that Cu segregates in the CdS, a phenomenon that is commonly observed in devices after back-contact processing and/or stress conditions.

Diffusion-Segregation Model: Pseudo-Binary Diffusion Couple Formulation



POhenomenological Flux Eq.

Mobility



Migration Flux

$I - A_{Cu}$ **Migration Potential** $\Delta H_{\mathrm{Cu}-p}^{i} = -\left(E_{D}^{i} + \phi_{\mathrm{Cu}-p}^{i}\right)$ **Segregation Enthalpy**

 $H_{\rm seg} = \Delta H_{{\rm Cu}-p} - \Delta H_{{\rm Cu}-p'}$



Migration Potential Near a Pseudo-Binary Diffusion Couple Interface



Device-Processing Simulation Results: High-Diffusivity Case

Device-Processing Simulation Results: Low-Diffusivity Case





Distance (lattice constants)

Figure 1. Schematic illustration of the ideal-solution Cu migration potential near a hypothetical material interface.

Distance (µm)

Figure 2. Device-processing simulation of Cu migration in CdTe PV device for the high-diffusivity case.

Distance (µm)

Figure 3. Device-processing simulation of Cu migration in CdTe PV device for the low-diffusivity case.

Survey of Cu Diffusivities and Solubilities in CdTe and CdS

	CdTe:Cu	diffusivity	/ data	
D ₀ (cm ² s ⁻¹)	E _D (eV)	Ref.	SC or PX	Diffusion mode
1.70E-06	0.24	[1]		
6.65E-05	0.57	[2]	SC	low
7.30E-07	0.33	[3]		
1.30E-06	0.29	[4]	PX	high
8.20E-08	0.64	[5]		
3.70E-04	0.67	[6]		
9.57E-04	0.7	[7]		
	CdTe:Cu	solubility	/ data	
C ₀ (cm ⁻³)	E_a (eV)	Ref.		
1.56E+23	0.55	[2]	SC	low
~2E+17	~0	[4]	PX	high
3.73E+24	0.68	[8]		
	CdS:Cu	diffusivity	' data	
D ₀ (cm ² s ⁻¹)	E_D (eV)	Ref.		
1.20E-02	1.05	[9]	SC	
2.10E-03	0.96	[10]	SC	
1.60E-03	0.77	[11]	SC	
	0.95	[12]	SC	
6.00E-09	0.5	[13]	PX	
	1.0	[14]	SC	
	CdS:Cu	solubility	data	
C ₀ (cm ⁻³)	E_a (eV)	Ref.		
8.00E+21	0.27	[13]	PX	
6.60E+22	0.505	[10]	SC	

Long-Term Stability Simulation Results: High-Diffusivity Case

Long-Term Stability Simulation Results: Low-Diffusivity Case

SIMS Depth Profile



Figure 5. Long-term stability simulation of Cu migration in CdTe PV device for the low-



Figure 6. Typical SIMS profile of a ZnTe:Cu back-contacted device after



Figure 4. Long-term stability simulation of

Cu migration in CdTe PV device for the







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